



XTMT10N122L

100V N-Channel MOSFET

Product Description

BV_{DSS}	100	V
I_D	120	A
$R_{DS(ON),Typ.}$	3.6	m Ω

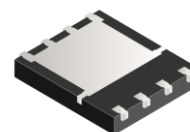
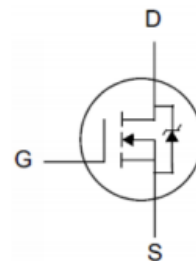
General Features

- Advanced technology and cellular structure
- $R_{DS(ON),typ.}=3.6m\Omega@V_{GS}=10V$
- Low Gate Charge Minimize Switching Loss
- Fast Recovery Body Diode

Applications

- Power management of uninterruptible power supply and inverter system

封装 Package



PDFN 5×6

Device	Package	Marking
XTMT10N122L	PDFN5*6	XTMT10N122L

Absolute Maximum Ratings $T_j=25^\circ\text{C}$

Symbol	Parameter	Value	Unit
V_{DSS}	Drain-to-Source Voltage	100	V
V_{GSS}	Gate-to-Source Voltage	± 20	
I_D	Continuous Drain Current	120	A
I_{DM}	Pulsed Drain Current at $V_{GS}=10V$	480	
E_{AS}	Single Pulse Avalanche Energy	780	mJ
P_D	Power Dissipation	208	W
$T_J \& T_{STG}$	Operating and Storage Temperature Range	-55 to 150	$^\circ\text{C}$

Caution: Stresses greater than those listed in the "Absolute Maximum Ratings" may cause permanent damage to the device.



Thermal Characteristics

Symbol	Parameter	Value	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	0.6	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	62.5	

Electrical Characteristics $T_j=25^\circ\text{C}$

OFF Characteristics

Symbol	Parameter	Min	Typ	Max	Unit	Test Condition
BV_{DSS}	Drain-to-Source Breakdown Voltage	100	-	-	V	$V_{GS}=0V, I_D=250\mu A$
I_{DSS}	Drain-to-Source Leakage Current	-	-	1	μA	$V_{DS}=100V,$ $V_{GS}=0V, T_J=25^\circ C$
I_{GSS}	Gate-to-Source Leakage Current	-	-	± 100	nA	$V_{GS}=\pm 20V, V_{DS}=0V$

ON Characteristics

Symbol	Parameter	Min	Typ	Max	Unit	Test Condition
$R_{DS(ON)}$	Static Drain-to-Source On-Resistance	-	3.6	4.5	m Ω	$V_{GS}=10V, I_D=50A$
$V_{GS(TH)}$	Gate Threshold Voltage	2.0	-	4.0	V	$V_{DS}=V_{GS}, I_D=250\mu A$

**Dynamic Characteristics**

Symbol	Parameter	Min	Typ	Max	Unit	Test Condition
C_{iss}	Input Capacitance	-	7266	-	pF	$V_{GS}=0V$, $V_{DS}=50V$, $f=1.0MHz$
C_{rSS}	Reverse Transfer Capacitance	-	24	-		
C_{oss}	Output Capacitance	-	864	-		
Q_g	Total Gate Charge	-	114	-	nC	$V_{DD}=50V, I_D=20A$, $V_{GS}=10V$
Q_{gs}	Gate-to-Source Charge	-	37	-		
Q_{gd}	Gate-to-Drain (Miller) Charge	-	26	-		

Resistive Switching Characteristics

Symbol	Parameter	Min	Typ	Max	Unit	Test Condition
$t_{d(ON)}$	Turn-on Delay Time	-	32	-	nS	$V_{DD}=50V, I_D=50A$ $V_{GS}=10V, R_G=3.0\Omega$
t_{rise}	Rise Time	-	50	-		
$t_{d(OFF)}$	Turn-Off Delay Time	-	83	-		
t_{fall}	Fall Time	-	31	-		

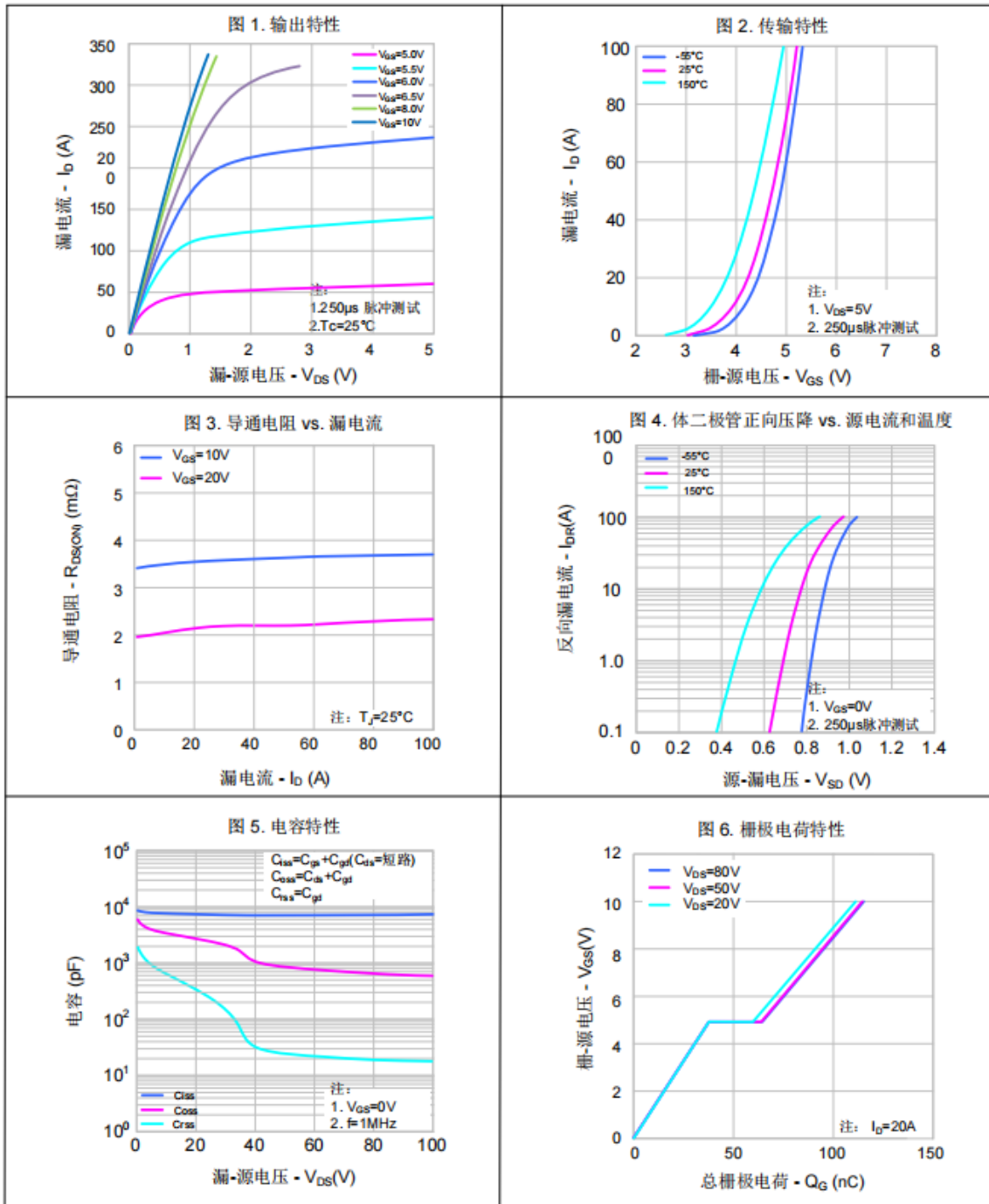
Source-Drain Body Diode Characteristics

Symbol	Parameter	Min	Typ	Max	Unit	Test Condition
I_{SD}	Continuous Source Current	-	-	120	A	Integral PN-diode in MOSFET
I_{SM}	Pulsed Source Current	-	-	480		
V_{SD}	Diode Forward Voltage	-	-	1.4	V	$I_S=50A, V_{GS}=0V$
t_{rr}	Reverse Recovery Time	-	77	-	ns	$I_F=50A$, $diF/dt=100A/\mu s$
Q_{rr}	Reverse Recovery Charge	-	0.18	-	uC	

[1] Pulse width $\leq 380\mu s$; duty cycle $\leq 2\%$

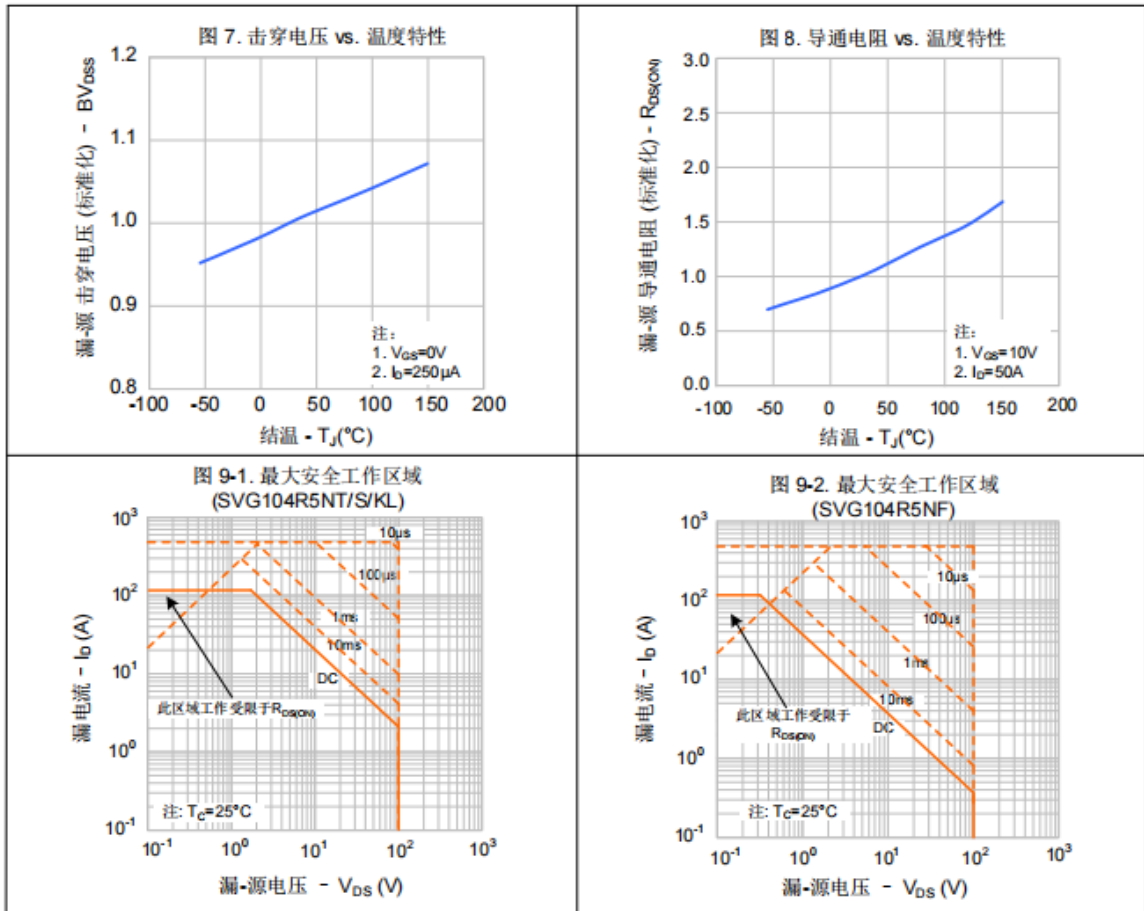


Typical Characteristics(Cont.)





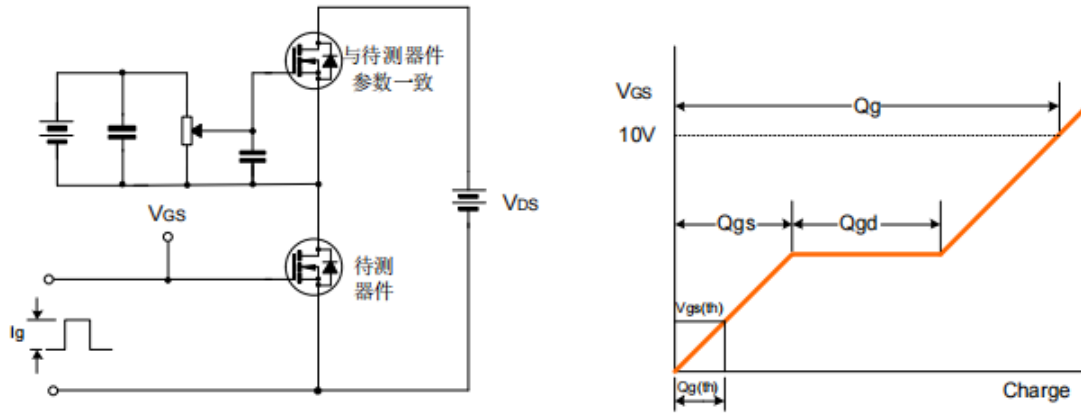
Typical Characteristics(Cont.)



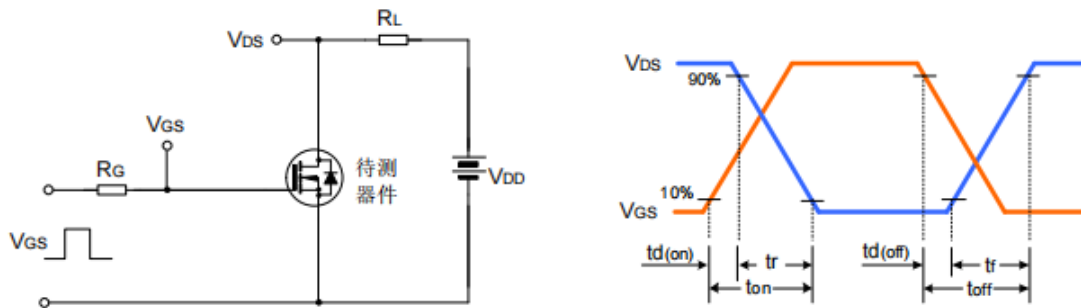


Test Circuits and Waveforms

栅极电荷量测试电路及波形图



开关时间测试电路及波形图



EAS测试电路及波形图

